

Form PTO 1449
Rev 7-80U.S. Dept of Commerce
Patent & Trademark Off.Atty. Docket No.
99-TK-553SSSerial No.
09/410,974Applicant
Jones et al.LIST OF PRIOR ART CITED BY APPLICANT
(Use several sheets if necessary)Filing Date
10/1/99Group
2737

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
AA <i>JMP</i>	5,386,565	01/31/95	Tanaka et al.	395/700	01/11/91
AB <i>JMP</i>	5,423,050	06/06/95	Taylor et al.	395/575	09/23/94
AC <i>JMP</i>	5,434,804	07/18/95	Bock et al.	364/579	12/29/93
AD <i>JMP</i>	5,440,705	04/30/90	Wang et al.	395/421.1	04/30/90
AE <i>JMP</i>	5,448,576	10/29/92	Russell	371/22.3	09/05/95
AF <i>JMP</i>	5,452,432	09/19/95	Macachor	395/425	07/23/93
AG <i>JMP</i>	5,455,936	10/03/95	Maemura	395/183.11	04/28/94
AH <i>JMP</i>	5,483,518	01/09/96	Whetsel	370/13	04/24/95
AI <i>JMP</i>	5,488,688	01/30/96	Gonzales et al.	395/183.1	03/30/94
AJ <i>JMP</i>	5,570,375	10/29/96	Tsai et al.	371/22.3	05/10/95
AK <i>JMP</i>	5,590,354	12/31/96	Klapproth et al.	395/800	07/28/94

FOREIGN COUNTRIES

DOC. NO.	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION
AL <i>JMP</i> EP0165600B1	11/21/91	Europe	G06F 13/36	English
AM <i>JMP</i> EP0636976A1	02/01/95	Europe	G06F 11/00	English

OTHER PRIOR ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGE, ETC.)

AN *JMP* Richard York; Real Time Debug for System-on-Chip Devices; June 1999; Pages 1-6EXAMINER *JMP*

DATE CONSIDERED 10-23-2002

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with PEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449
Rev 7-80U.S. Dept of Commerce
Patent & Trademark OfficeAtty. Docket No.
99-TK-553SSSerial No.
09/410,974Applicant
Jones et al.LIST OF PRIOR ART CITED BY APPLICANT
(Use several sheets if necessary)

JUN 29 2000

Filing Date
10/1/99Group
2737

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
AO <i>DMP</i>	5,596,734	01/21/97	Ferra	395/825	12/19/95
AP <i>DMP</i>	5,627,842	05/06/97	Brown et al.	371/22.3	06/04/96
AQ <i>DMP</i>	5,704,034	12/30/97	Circello	395/183.14	08/30/95
AR <i>DMP</i>	5,708,773	01/13/98	Jeppesen, III et al.	395/183.06	07/20/95
AS <i>DMP</i>	5,737,516	04/07/98	Circello et al.	395/183.14	08/30/95
AT <i>DMP</i>	5,768,152	06/16/98	Battaline et al.	364/551.01	08/28/96
AU <i>DMP</i>	5,771,240	06/23/98	Tobin et al.	371/22.1	11/14/96
AV <i>DMP</i>	5,781,558	07/14/98	Inglis et al.	371/21.1	05/13/97
AW <i>DMP</i>	5,828,825	10/27/98	Eskandari et al.	395/183.03	04/12/96
AX <i>DMP</i>	5,944,841	08/31/99	Christie	714/38	04/15/97
AY <i>DMP</i>	5,950,012	09/07/99	Shiell et al.	395/712	03/07/97

FOREIGN COUNTRIES

DOC. NO.	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION
AZ <i>DMP</i> EP0636976B1	02/01/95	Europe	G06F 11/00	English
BA <i>DMP</i> EP0702239A2	03/20/96	Europe	G01R 31/3173	English

OTHER PRIOR ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGE, ETC.)

EXAMINER

[Signature]

DATE CONSIDERED 10-24-2002

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with PEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449
Rev 7-80U.S. Dept of Commerce
Patent & Trademark OfficeAtty. Docket No.
99-TK-553SSSerial No.
09/410,974Applicant
Jones et al.LIST OF PRIOR ART CITED BY APPLICANT
(Use several sheets if necessary)Filing Date
10/1/99Group
2737

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
BB <i>JMP</i>	5,956,477	09/21/99	Ranson et al.	395/183.06	11/25/96
BC <i>JMP</i>	5,978,874	11/02/99	Singhal et al.	710/107	07/01/96
BD <i>JMP</i>	5,978,902	11/02/99	Mann	712/227	12/17/97
BE <i>JMP</i>	5,983,017	11/09/99	Kemp et al.	395/704	11/12/96
BF <i>JMP</i>	5,983,379	11/09/99	Warren	714/727	10/29/97
BG <i>JMP</i>	5,251,311	10/05/93	Kasai	395/425	10/11/90
BH <i>JMP</i>	4,814,981	03/21/89	Rubinfeld	364/200	10/18/86
BI <i>JMP</i>	5,598,551	01/28/97	Barajas et al.	395/484	02/15/96
BJ <i>JMP</i>	5,613,153	03/18/97	Arimilli et al.	395/821	10/03/94
BK <i>JMP</i>	5,724,549	03/03/98	Selgas et al.	395/468	10/01/93
BL <i>JMP</i>	5,848,247	12/08/98	Matsui et al.	395/284	09/07/95

FOREIGN COUNTRIES

DOC. NO.	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION
BM <i>JMP</i> EP0720092A1	07/03/96	Europe	G06F 11/00	English
BN <i>JMP</i> EP0945805A1	09/29/99	Europe	G06F 12/08	English

OTHER PRIOR ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGE, ETC.)

EXAMINER *JMP*

DATE CONSIDERED

10-24-2002

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with PEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449
Rev 7-80U.S. Dept of Commerce
Patent & Trademark OfficeAtty. Docket No.
99-TK-553SSSerial No.
09/410,974Applicant
Jones et al.LIST OF PRIOR ART CITED BY APPLICANT
(Use several sheets if necessary)Filing Date
10/1/99Group
2737

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
BO <i>JMP</i>	5,608,881	03/04/97	Masumura et al.	395/306	10/29/93
BP <i>JMP</i>	5,862,387	01/19/99	Songer et al.	395/728	06/27/97
BQ <i>JMP</i>	5,896,550	04/20/99	Wehunt et al.	395/846	04/03/97
BR <i>JMP</i>	5,953,538	09/14/99	Duncan et al.	395/842	11/12/96
BS <i>JMP</i>	5,682,545	10/28/97	Kawasaki et al.	395/800	06/07/95
BT <i>JMP</i>	5,530,965	06/25/96	Kawasaki et al.	395/800	08/21/95
BU <i>JMP</i>	5,832,248	11/03/98	Kishi et al.	395/376	11/14/96
BV <i>JMP</i>	5,608,881	03/04/97	Masumura et al.	395/306	10/29/93
BW <i>JMP</i>	5,930,523	07/27/99	Kawasaki et al.	395/800.32	04/03/98
BX <i>JMP</i>	5,930,833	07/27/99	Yoshioka et al.	711/210	08/21/97
BY <i>JMP</i>	5,778,237	07/07/98	Yamamoto et al.	395/750.04	12/14/95

FOREIGN COUNTRIES

DOC. NO.	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION
BZ <i>JMP</i> EP0933926A1	08/04/99	Europe	H04N 5/00	English
CA <i>JMP</i> EP0959411A1	11/24/99	Europe	G06F 13/24	English

OTHER PRIOR ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGE, ETC.)

EXAMINER *JMP*

DATE CONSIDERED 10-24-2002

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with PEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449
Rev 7-80U.S. Dept of Commerce
Patent & Trademark Off.Atty. Docket No.
99-TK-553SSSerial No.
09/410,974Applicant
Jones et al.Filing Date
10/1/99Group
2737LIST OF PRIOR ART CITED BY APPLICANT
(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
CB <i>JMP</i>	5,796,978	08/18/98	Yoshioka et al.	395/416	09/07/95
CD <i>JMP</i>	5,835,963	11/10/98	Yoshioka et al.	711/207	09/07/95
CE <i>JMP</i>	5,848,247	12/08/98	Matsui et al.	395/284	09/07/95
CF <i>JMP</i>	5,860,127	01/12/99	Shimazaki et al.	711/167	05/24/96
CG <i>JMP</i>	5,867,726	02/02/99	Ohsuga et al.	395/800.32	04/10/96
CH <i>JMP</i>	5,884,092	03/16/99	Kiuchi et al.	395/800.35	10/04/96
CI <i>JMP</i>	5,918,045	06/29/99	Nishii et al.	395/584	10/17/97
CJ <i>JMP</i>	5,774,701	06/30/98	Matsui et al.	395/556	07/10/95
CK <i>JMP</i>	5,657,273	08/12/97	Ayukawa et al.	395/189.01	11/15/95
CL <i>JMP</i>	5,751,621	05/12/98	Arakawa	364/748.07	11/13/95
CM <i>JMP</i>	5,479,652	12/26/95	Dreyer et al.	395/183.06	10/21/94

FOREIGN COUNTRIES

DOC. NO.	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION
CN <i>JMP</i> JP8320796A	12/03/96	Japan	G06F-009/46	Japanese
CO <i>JMP</i> JP9212358A	08/15/97	Japan	G06F-009/38	Japanese
CP <i>JMP</i> JP8329687A	12/13/96	Japan	G11C-015/00	Japanese

OTHER PRIOR ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGE, ETC.)

EXAMINER *J. M. P.*

DATE CONSIDERED

10-24-2002

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with PEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Serial No.
09/410,974

Group
2737

[illegible]

DOC. NO.	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION
CQ <i>EMP</i> JP9311786A	12/02/97	Japan	G06F-009/38	Japanese
CR <i>EMP</i> JP10106269A	04/24/98	Japan	G06F-012/08	Japanese

10-24-2002

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with PEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

